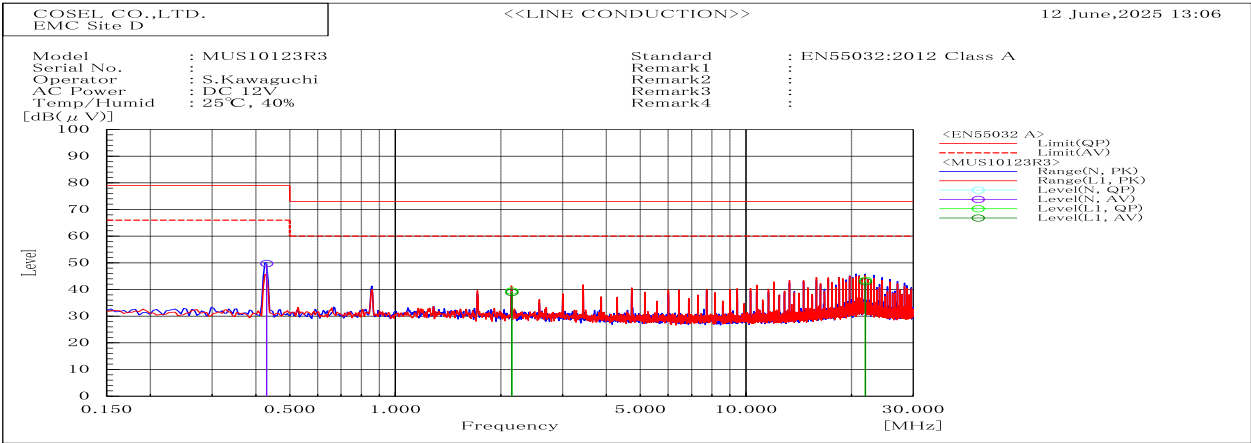
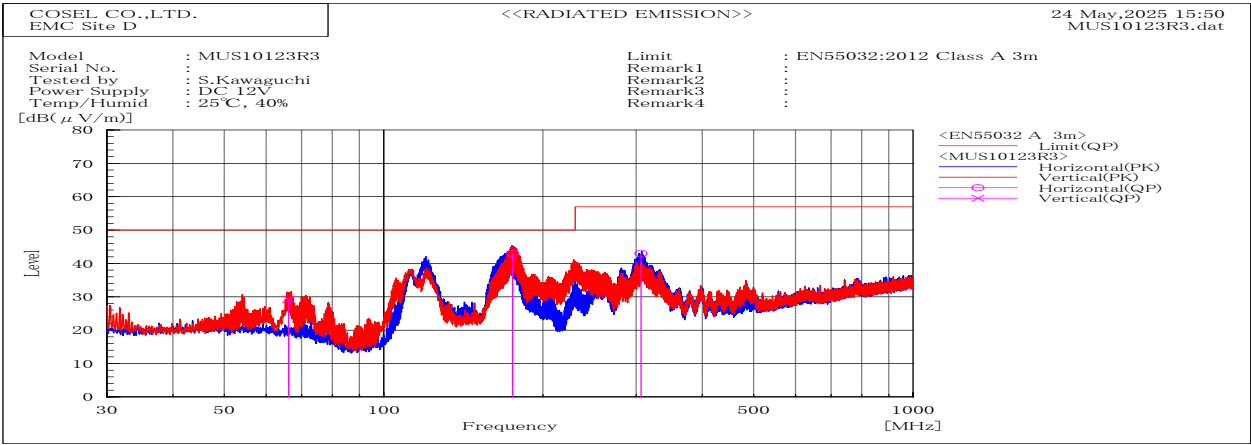


DATA SHEET		Date	12-Jun-25
Model	MUS10123R3	Temp.	25 degreeC
Test	EMI Line conduction & Radiated emission	Humid.	40 %RH
		Tested by	S.Kawaguchi



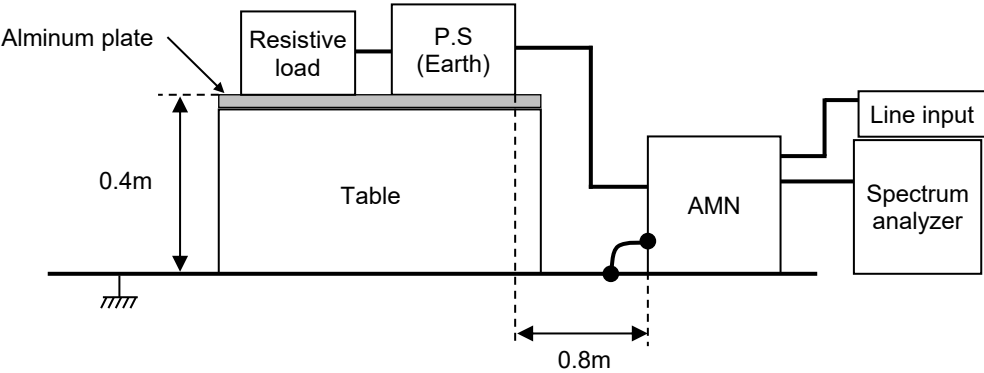
Frequency MHz	Line	Level dB(μV)		Limit dB(μV)		Margin dB		Pass/Fail	Remark
		QP	AV	QP	AV	QP	AV		
2.148	L1	39.4	38.9	73	60	33.6	21.1	Pass	
21.91	L1	43.4	42.9	73	60	29.6	17.1	Pass	
0.429	N	49.9	49.7	79	66	29.1	16.3	Pass	



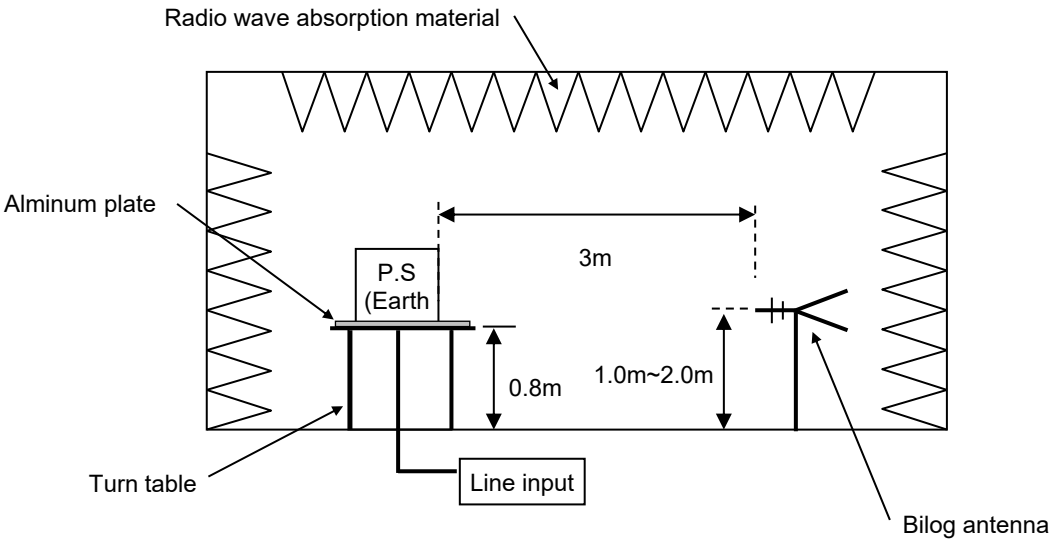
Frequency MHz	Polarization	Stability	Level dB(uV/m)		Margin dB	Pass/Fail	Height cm	Angle deg	Remark
			QP	QP					
175.236	H	Stable	43	50	7	Pass	190.2	248.7	
66.15	V	Stable	29.3	50	20.7	Pass	100	110.1	
306.327	H	Stable	43	57	14	Pass	103.9	89.3	

DATA SHEET		Date	12-Jun-25
Model	Circuit used for measurement	Temp.	25 degreeC
Test	EMI Line conduction & Radiated emission	Humid.	40 %RH
		Tested by	S.Kawaguchi

1. Line conduction



2. Radiated emission



Conditions

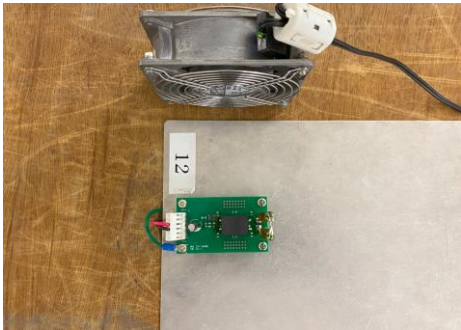
Test : EMI
 Model Name: MUS10□□

○Photographs of Test Set-Up

LINE CONDUCTION



RADIATED EMISSION



○Testing circuitry

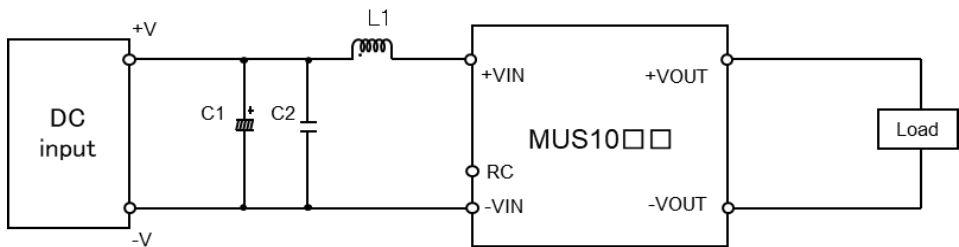


Fig.1 MUS10□□ Testing circuitry

C1 :	MUS1005□	25V 1500 μ F	Electric capacitor (LXZseries NIPPON CHEMI-CON)
	MUS1012□	50V 100 μ F	Electric capacitor (UPWseries NICHICON)
	MUS1024□	—	—
	MUS1048□	—	—
C2 :	MUS1005□	16V 22 μ F	Ceramic capacitor (GRM31CC71C226M MURATA MANUFACTURING)
	MUS1012□	25V 10 μ F	Ceramic capacitor (CM316X7R106K25AT KYOCERA)
	MUS1024□	50V 4.7 μ F	Ceramic capacitor (GRM31CR71H475K MURATA MANUFACTURING)
	MUS1048□	100V 2.2 μ F	Ceramic capacitor (C3216X7S2A225KT TDK)
L1 :	MUS1005□	5000mA 2.2 μ H	Inductor(LQH5BPN2R2N38 MURATA MANUFACTURING)
	MUS1012□	3500mA 4.7 μ H	Inductor(LQH5BPN4R7N38 MURATA MANUFACTURING)
	MUS1024□	1600mA 22 μ H	Inductor(LQH5BPN220M38 MURATA MANUFACTURING)
	MUS1048□	1100mA 47 μ H	Inductor(LQH5BPN470M38 MURATA MANUFACTURING)